

How to generate high quality tests for digital systems

Ubar, Raimund-Johannes; Aarna, Margit; Kruus, Helena; Raik, Jaan 2004 International Semiconductor Conference : 27th edition, October 4-6, 2004, Sinaia, Romania : CAS 2004 proceedings. Volume 2 2004 / p. 459-462 : ill
<http://dx.doi.org/10.1109/SMICND.2004.1403048>

Implementation-independent functional test for transition delay faults in microprocessors

Oyeniran, Adeboye Stephen; Ubar, Raimund-Johannes; Jenihhin, Maksim; Raik, Jaan 2020 23rd Euromicro Conference on Digital System Design (DSD), 26-28 August 2020, Kranj, Slovenia 2020 / p. 646-650 <https://doi.org/10.1109/DSD51259.2020.00105>